

SEARCHED

Class	Sub.	Date	Exmr.
704	231	20 APR '04	DAN
705	232		
725	234		
709	243		
700	248		
	234		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

STIC PLUS SCAN Search	Date	Exmr.
EAST Full Text SEARCH NPL SCAN SEARCH - IEEE - ACM - JAPAN PATENT	20 APR '04	DAN

BEST AVAILABLE COPY

INTERFERENCE SEARCHED

Class	Sub.	Date	Exmr.